Tool name: Raman spectrometer, Renishaw InVia

Purpose: Raman scattering and photoluminescence measurements for characterization of materials.

Description:

- Available wavelength: 244 nm (double frequency with 488 nm Ar^+ laser)

  325 nm (He-Cd laser)

  457.9 nm, 488 nm, 514.5 nm (Ar^+ laser)

  632.8 nm (He-Ne laser)

  785 nm (Diode laser)

- Grating: 600 grooves/mm (Visible/NIR), 1200 grooves/mm (NIR), 2400 grooves/mm (Visible), 3600 grooves/mm (UV)

- Combined with open space optical microscope (in-situ Raman and photoluminescence measurements with electrical probes)

- Motorized translation sample stage for Raman mapping (point-by-point mapping, line focus mapping)

Photo: